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				Art Unit	
				Yoshitaka Sugawara	
				Examiner Name	
Sheet 1 of 1				Attorney Docket Number 3688KE-1	

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-kind Code ^{2 (if known)}	Publication Date MM-DD-YYYY	Name of Patentee of Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US-			
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FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Country Code ³	Number ⁴ : Kind Code ⁵ (if known)			
AS		JP	- 08-018030	01/19/1996	Fuji Electric Co., Ltd.	
		JP	- 09-148681	06/06/1997	Sumitomo Electric Ind. Ltd.	
		JP	- 10-022495	01/23/1998	Meidensha Corp.	
		JP	- 2001-217363	08/10/2001	Hitachi Ltd.	
		JP	- 2002-325355	11/08/2002	The Kansai Electric Power Co., Inc.	
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OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)		
Examiner Initials*	Cite No. ¹	
AS		"4H-SiC HIGH POWER SIJFET MODULE" by Sugawara et al., ISPSD 2003, April 14-17, Cambridge, UK, pp. 127-130.
		"Structure of Stacking Faults Formed During the Forward Bias of 4H-SiC p-i-n Diodes" by Twigg et al., Applied Physics Letters, Vol. 82, No. 15, 14 April 2003, pp. 2410-2412
		"Recent Progress in SiC Power Device Developments and Application Studies" by Sugawara, ISPSD, April 14-17, 2003, Cambridge, UK., pp. 10-18.
		"4H-SiC p-n Diodes and Gate Turnoff Thyristors for High-Power, High-Temperature Applications" by Agarwal et al., Pergamon, Solid State Electronics 44 (2000) pp. 303-308.

Examiner Signature	/A Sefer/	Date Considered	08/18/2006
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*EXAMINER: Initial if reference is considered, whether or not citation is in conformance and not considered. Include copy of this form with next communication to applicant.